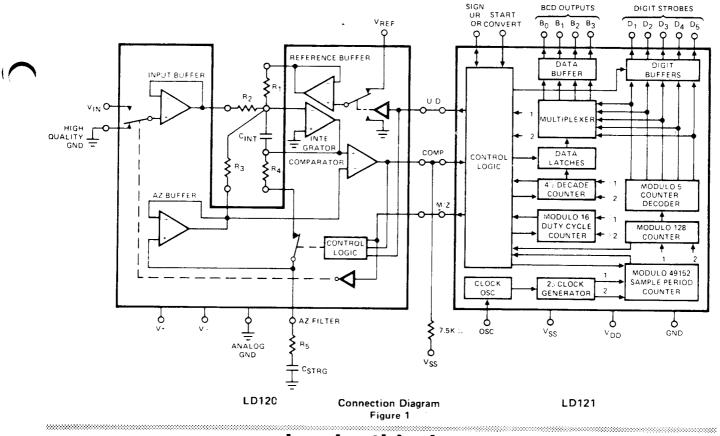


Siliconix, Inc. has developed a 4½ digit DVM system for low-cost, high-performance applications. The set consists of a monolithic PMOS synchronous 18-pin digital processor (LD 121) and a monolithic bipolar-PMOS 16-pin analog processor (LD 120).

The two-chip system uses a charge-balancing technique for A/D conversion called "quantized feedback." The conversion technique balances the charge supplied by a current proportional to the input voltage, over a measured interval, with an accumulation of quantized charges equal to a BCD count. The units of quantized charge are provided through pulsewidth modulation of a reference current.

Figure 1 illustrates the functional block diagram of the A/D converter with external components required for proper circuit connection.



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system operation

The LD 120/LD 121 system performs a ratiometric A/D conversion which may be used over a fullscale range from 1.9999 volts or 199.99 millivolts. The 199.99 mV range is capable of 10 μ V resolution.

The following output information is available: two overrange signals, underrange, sign and 4½ digits of multiplexed BCD data. All outputs are TTL compatible. Overrange is also indicated by blinking digit. strobes above 20,000 counts. An input is provided to inhibit this feature at user option.

The system does require three supply voltages (12 V, -12 V, 5 V) and a stable reference voltage. An internal oscillator can be used to generate a clock frequency but is not recommended for design. For improved CMRR, an external clock source is recommended.

system performance

Discussions with Siliconix are currently under way to obtain 200 mV range specifications. Specifications at this range are not yet available in data books. Up-to-date comprehensive specs for the LD 120 and LD121 are shown in Table 1. The following discussion covers what each system performance specification means, and how it compares to typical measured values.

linearity and noise

Linearity error is determined by measuring the maximum deviation of the output reading from a straight line drawn between the value of the converter's zero offset and the full-scale value. Noise error is defined as internal noise generated within the chip and is measured as the amount of fluctuation of the output reading. Linearity and noise errors are difficult to separate, thus an error measurement will constitute a composite of linearity error and noise error.

Samples of the LD 120/LD 121 tested at Tektronix showed that the typical count deviation at 25°C was -1 to +2 counts for the 200 mV scale. Maximum error due to linearity and noise for the 200 mV scale at 25°C is ± 4 counts.

zero drift

Zero drift is the amount of counts the output will drift over temperature with zero input signal. The limits of zero drift for samples tested was ± 2 counts. Siliconix specifies maximum zero drift as ± 5 counts and typical zero drift as ± 1 count for the 2 V and 200 mV scales.

gain temperature coefficient

Gain error is the departure of the actual output reading from expected output reading for a full-scale input voltage. At a particular temperature, gain error is nulled by the application of a gain adjustment.

The gain temperature coefficient is the amount the output reading will vary per change in temperature for a full-scale input voltage. Figure 2 illustrates the observed gain errors associated with temperature changes. Siliconix specifies that the output reading will vary a maximum of 15 ppm/ \triangle° C and typically 5 ppm/ \triangle° C for the 2 V and 200 mV ranges.

accuracy

The term **accuracy** describes the overall performance of a converter. It measures how closely the output of the actual A/D converter approaches the output of an ideal model.

Accuracy includes all error sources, principally, linearity error, noise error, zero offset error, temperature coefficients and power supply changes. Since the LD 120/LD121 converter has fairly high resolution, circuit board layout becomes a critical factor for maximizing accuracy. Contact me in Component Engineering for board layout considerations.

conclusion

The LD 120/LD121 converter set will cost approximately \$15.00 in 1000 lot quantities, and should be considered for applications involving 4½ digit DVM systems. Samples tested show that the LD 120/LD 121 can be successfully used on the 200 mV scale with proper design considerations.

For more information about the LD 120/LD 121, please contact Chris Martinez on ext. 7709.

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. 6.5

41/2 digit A/D converter Table 1: Electrical Characteristics

| | | СНА | ARACTERISTIC | MIN | TYP | МАХ | UNITS | | CONDITIONS ; V-, $V_{DD} = -12 V$, TEMP. | |
|--------|-----------------------|-----------------|------------------------|-----|------------|------------|-------------------------------|---------------------------|---|--|
| | | · · · | | -1 | ±¼ | +1 | | 2 V | | |
| | | | Linearity | -2 | ±1/2 | +2 | Counts | 200 m∨ | 25°C | |
| | | | Stability | | ±1/3 | <u>+</u> 1 | | 2 V | a=9. | |
| | S Y | | (noise) | | <u>+</u> ½ | ±2 | Counts | 200 mV | 25°C | |
| (N | S Y S T E | | | | -2 to +1 | | | | 0°c | |
| | É M | | Linearity + | | -1 to +2 | | Counts | 200 mV | 25°C | |
| | lotes & 3) | | Stability* | | -2 to +1 | | - | | 50°C | |
| | u 0, | | Zero drift | | | | | | 70 [°] C | |
| | | | Gain T.C. | | ±2* | | Counts PPM/ ^O C | 2 V, 200 mV | 25°C to 75°C | |
| | | NMRR | , Gam 1.0. | | see fig. 2 | 15 | PPM/ C | 2 V, 200 mV | 0°C to 70°C | |
| | | PSRR | | | 40 | | | dB | 25°C | |
| | | ļ | | | 80 | | | | 25°C | |
| | P O | V _{SS} | | 4 - | 5 | 6 | v | V _{SS} = 5 | 5 V, T _A = 25°C | |
| | E E | | | 9 | -12 | -15 | | | | |
| | R | ISS | (Note 4) | | 12 | 15 | mA | | <u></u> | |
| | | VINH | Comparator Input | 3.5 | | | | | | |
| | | VINL | | | | 3 | | | | |
| | | VINH | Sign/Or/Ur (Note 5) | 3.5 | | | | | | |
| | | VINL | Blink Inhibit | | | 0.5 | v | Guaranteed In | out Threshold Voltage | |
| | N | VINH | Start | 3.5 | | | | | out intesnoid vortage | |
| L | P U | VINL | | | | 0.5 | | | | |
| D 1 | T S | VINH | Oscillator IN | 3.5 | | | | | | |
| 2 1 | | VINL | | | | 3 | | | | |
| ç | | INH | Sign/OR/UR (Note 5) | | | 170 | | μA V _{IN} = 0 V | | |
| D | | INL | Start | | | -170 | <u> </u> | V _{IN} = 5 V | | |
| l G | | INL | Oscillator | | | 1.4 | mA | V _{IN} = -3.5 V | · · · · · · · · · · · · · · · · · · · | |
| Î T | | V _{OH} | Bit Lines, Sign/OR/UR | 2.4 | | | | ^I OH = -10 µA | | |
| À | 0 | V _{OL} | Digit Strobes | | | 0.5 | ľ | I _{OL} = 1.6 mA | | |
| _ | T | v _{oн} | M/Z | 4.0 | | | ~ | I _{OH} = −150 µA | A | |
| | U T | VOL | | | | 0.5 | × | l _{Ol} = 0.8 mA | | |
| | S | v _{он} | | 4.0 | Ì | | ľ | I _{OH} = -0.5 mA | | |
| | | V _{OL} | | | . | 0.5 | | I _{OL} = 0.8 mA | | |
| | D | ^t P | Start Convert (Note 6) | 20 | | | μs | | ····· | |
| | Y N | fosc | | 50 | | 250 | kHz | 50% Duty Cycle | e | |
| | AM | | Rep Rate | 78 | | 470 | Hz | fosc + 640 | | |
| | I C | | Duty Cycle | | 15 | | | | ······ | |
| | | | Interdigit Blanking | | 25 | | % | | <u> </u> | |

* Typical values measured at Tektronix

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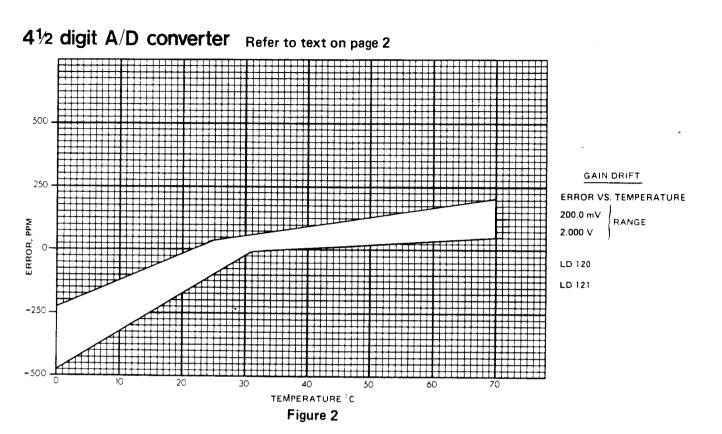
| | | | | MIN | ТҮР | мах | UNITS | TEST CONDITIONS V+ = 12 V; V-, V _{DD} = -12 V, V _{SS} = 5 V, T _A = 25 °C |
|-------------|-----------------------|---------------------------------------|---------------------------------|------|------|------|-------|---|
| | P | V+ | | 9 | 12 | 15 | | |
| | | V | | -9 | -12 | -15 | | |
| | WE | 1+ | | | | 3.5 | | |
| | R | 1- | | | | -3 | mA | |
| | | IGND | | 0 | | -2 | mA | M/Z, U/D = 2.4 V |
| | 1 | ISOURCE | | -50 | 100 | | | V _{IN} = 2 V, Buff Out = 0 V |
| | P | ISINK | | 400 | 800 | | μA | V _{IN} = −2 V, Buff Out = 0 V |
| | U T | IN | | | 2 | | - 0 | V _{IN} = ±2.8 V |
| | В | IN | • | | 40 | | рА | T _A = 70°C, V _{IN} = ±2.8 V |
| L | UF | CMRR | | | -72 | | dB | |
| D 1 | F | VIN | (Note 7) | -5 | | 5 | v | |
| 2 | A Z B U F | ISOURCE | | | -100 | | | |
| J C | | ISINK | • | | 800 | | μA | |
| L | | ISTRG | | | 100 | | pА | T _A = 70°C |
| N E | | VOFFSET | | 50 | | 50 | mV | V _{OUT} = 0 V |
| = 4 7 | | · · · · · · · · · · · · · · · · · · · | Switch Resistance (on) (Note 8) | | 6 | 20 | kΩ | V _{STRG} = -4 V, I _{DS} = 30 µA |
| | RB EU | SOURCE | | -400 | -800 | | | V _{IL} (U/D IN) = 0.8 V, V _O = 0 V |
| | E F F F | ISINK | | | 100 | | μA | V _{IH} (U/D IN) = 2.0 V, V _O = 2 V |
| i | | ISOURCE | (Note 9) | -50 | 100 | | | V _{IN} (Int. IN) = -100 mV, V _O = 0 V |
| | N T | ISINK | | 400 | 800 | | μA | V _{IN} (Int. IN) = 100 mV, V _O = 0 V |
| | | | Output Swing | -10 | | 10 | v | |
| | C O M | V _{OUT} | | -5 | | | v | R _L = 10k to +5 V, AZ FILTER IN = 100 mV |
| | P | V _{OFFSET} | | | ±5 | 1 | mV | INTEGRATOR OUT = 0 V |
| | | Чн | M/Z, U/D Inputs | | | 50 | nA | V _{IH} = 2.0 V |
| | [| IIL III | (m/2, 0/0) mputs | | | -100 | μA | V _{IL} = 0.8 V |

NOTES:

- 1. Bit width over which reading is stable 95% of the time.
- 2. System Parameters are not directly tested.
- 3. f_{OSC} = 163.84 kHz, V_{REF} = 6.8 V.
- 4. All outputs disconnected.
- 5. Pin characteristic only during D_4 strobe time.
- 6. Minimum positive going pulse width to initiate a conversion.
- 7. Maximum voltage for VINPUT (pin 1) or hi-quality GND (pin 2) for which linearity can be guaranteed.

Ż

- 8. VSTRG must be more positive than -4 volts.
- 9. Reference Source Impedance must be less than 10K Ω_{\star}



Second edition of sourcebook available

The second edition of the Engineering Sourcebook (Who, What, When, Where, How) is now available from Technical Communications.

The sourcebook is a general reference and resource guide for Tek engineers and support personnel. The book outlines the services provided by various design, evaluation and engineering support groups within the company. Specifically, who to contact, what is the function, when and how to make contact and where groups are located.

In addition to reorganizing and updating the information in the sourcebook, this edition incorporates divider tabs, an index and page numbers for easier reference.

If you would like a copy of the sourcebook, fill in the coupon below and return to delivery station 58-299.

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Component applications review described

The primary function of Component Applications Engineering is to conduct component application reviews of new instruments. Two to four weeks before DC is the best time to begin the reviews. Reviews before PR and again before ER can be helpful, but changes are more difficult to implement.

When one of the product introduction milestones (DC, PR or ER) is approaching, you may request a component applications review of your instrument. We will need a set of diagrams, a parts list, and an EIS (Engineering Instrument Specification) if there is one. To best evaluate mechanical component applications, we need an instrument for about a half day.

While designers regularly seek assistance from component engineers for new components, they may be unaware of some application problems with previously part-numbered components. Component Applications Engineering can warn you of probable availability problems, recommend less expensive, more reliable or better performing parts, and give some helpful tips on protecting sensitive devices. Now and then we can put you in touch with another designer who has already solved a problem similar to the one you're facing.

In addition, we have a library of applications notes which are available for reading and copying. The app notes are grouped by function – power supplies, audio, reliability, etc.

The NPI Guidebook briefly describes the component applications activities. Refer to Section II, 2.16; II, 3.21; and II, 4.25 in the guidebook.

To schedule a component applications review, or for other application assistance, contact Virg Tomlin (ext. 5302) or Jim Howe (ext. 5698).

Programmed memory devices assigned ~160" P/N

To alleviate problems with programmed memory devices the following plan is being put into effect.

All programmed memory devices (ROM, PROM, EPROM, EAROM, PAL, FPLA) will be given a newly designated Tek part number which is 160-xxxx-xx.

What does this mean to the engineer trying to part number a device for an instrument? It will require a certain amount of additional effort on the designer's part. The procedure will be as follows.

1. A PPIF will be submitted in the usual manner and a part number assigned.

2. Approximately one week prior to FER (Field Engineering Release) the engineer will furnish a device and a binary paper tape to Component Engineering, both containing the bit pattern. Component Engineering will verify that the contents of the two are identical and return the part to the engineer. The paper tape will then be sent to archiving for permanent storage. 3. The component engineer will sign off the spec indicating he/she has verified the contents.

4. The question may be asked: Why are we doing this? There are cases where instruments have been shipped and parts have failed in the field, but field personnel were unable to secure parts because the bit pattern was never documented except in the engineer's desk drawer. We wish to correct this situation.

We would also request that devices part numbered under the old 156-xxxx-xx not be changed to the new system. It would cause mass confusion.

Also, unprogrammed parts (EPROM, EAROM, PROM, etc.) will still have the 156-xxxx-xx. The 160-xxxx-xx is reserved for programmed versions only.

Any questions concerning MOS devices should be directed to Bob Goetz, ext. 6302, and for bipolar devices to Dave Sutherland, ext. 6301.

Call Dorothy Peterson, ext. 6336 for more details on the 160-xxxx-xx system.

code R F Z G Н W J S К A L В С D Μ N

Ceramic capacitor markings

It's important to remember that different manufacturers use different marking methods for identifying ceramic capacitors. Where one vendor might mark a 0.1 μ F \pm 20% capacitor "104M," another manufacturer might mark an identical capacitor ".1M."

When the capacitance is expressed in picofarads (pF), the value is usually identified by a three digit number, with the first two digits representing the first two significant figures, and the last digit indicating the number of zeros (i.e. "104" is 100,000 pF). If the value is less than 10 pF, the letter "R" is often used to indicate the decimal point. For example, "7R5" is 7.5 pF. Another method uses the number "9" to move the decimal point one place to the left, i.e. "759" is 7.5 pF.

When the tolerance is marked, a letter will be used after the value to indicate the tolerance. "103K" or ".01K" thus becomes $0.01\mu F \pm 10\%$ (see table below).

The temperature characteristic is usually shown as a group of three characters written below the capacitance value. For example, $\frac{02P}{25P}$ is 0.2µF -0-+100%, with a temperature range of +10°C to +85°C, and a maximum capacitance change of ±10%.

The following tables list the most commonly used tolerance and temperature characteristic codes. For more information on capacitor markings contact Harry Ford (58-299), ext. 6520.

| | Temp. range | code | Cap toleranc (%) | e code | | Tempe Coeff | rature icient | Temp. C Tolera | |
|---|------------------|--------|---------------------|-----------|----|----------------|------------------|-------------------|--------|
| | | | | | | РРМ | code | PPM/°C | coc |
| ~ | +10 +85 | Z5 | ±1 | F | | Stearlite | A8 | +10 | R |
| 1 | -30-+85 | Y5 | ±2 | G | | P120 | A7 | +15 | F |
| | -55+85 | X5 | ±3 | Н | | P100 | M7 | +20 | Z |
| | -55—+125 | X7 | ±5 | J | | P030 | B6 | +30 | Z G |
| | | W5 | | | | NPO (0) | C0 | +60 | н |
| | -55+150 | V5 | ±10 | К | | N030 | B1 | +100 | ` W |
| | | | ±20 | M | | N080 | U1 | +120 | Ĵ |
| | | | -20 - +80 | Z | | N150 | P2 | +150 | S |
| | | | -0 - +100 | P | | N220 | R2 | +250 | ĸ |
| | Single letter of | ode | +2290 | Ŵ | | N300 | B2 | +400 | A |
| | for temp. cha | 1. | Special | G | | N330 | S2 | +500 | Ĺ |
| | △C over temp | . code | Opeera | U | | N470 | T2 | +650 | R |
| | (%) | | L | | 1. | N500 | D2 | +860 | B C |
| | 7.5 | В | | | 1 | N650 | E2 | +900 | D |
| | +22 | C | Max. cap | code | | N750 | U2 | +1000 | M |
| | +2256 | E | (/0) | coue | | N1400 | F3 | +2500 | Ň |
| | | | | | | N1500 | P3 | 12300 | I N |
| | | | | | | N2200 | R3 | Not | |
| | | | ±1 | А | | N3300 | S3 | specified | 0 |
| | | | ±1.5 | В | | N4200 | G3 | specifieu | |
| | ppm/°C | | ±2.2 | Ċ | | N4700 | T3 | See. | |
| | 0 ± 30 | A | ±3.3 | Ď | | N5600 | H3 | See | Р |
| | | | | - | | P400 | 1 | appl. | • |
| | | | <u>+</u> 4.7 | F | | .P400 | W2 | spec. | |
| | | | ±7.5 | E F | | | | L | |
| | | | ±10 | P | | (.1M) | | | |
| | | | ±15 | R | | 259.2 | | | - |
| | | | ±22 | 5 | | Υ | | \sim | |
| 1 | | | +2233 | S T | | | | F | |
| | | | +2256 | ບໍ່ | | | 785 | | |
| | | | +22 | v | | | | | |
| | | | 122 | v | | | | | |
| | | | | | l | 11 11 | | | |

Capacitors: insulation resistance clarified

The insulation resistance of a capacitor can be quite critical in circuitry where current leakage through the capacitor can cause malfunction or undesirable results to occur. Examples of these applications are coupling and timing circuits.

Insulation resistance is often confused with the inherent "series resistance" of a capacitor. However, insulation resistance (IR) is a measure of leakage current and is referred to as the "parallel" or "shunt" resistance of the capacitor (see Figure).

Leakage current is composed of electrons that make their way through the dielectric itself, around the edges and across the surfaces of the dielectric, and between the leads.

In general, if we double the dielectric area, we also double the paths for electrons to flow through the dielectric, resulting in double the leakage current (one-half the insulation resistance). This inverse ratio between capacitance and insulation resistance for any given dielectric makes it possible for a capacitor manufacturer to specify a given IR for all capacitance values in a product line.

This is done by multiplying the insulation resistance (ohms) times the capacitance (farads) to arrive at a constant value of ohms x farads. Manufacturers commonly specify IR as meg $\Omega\mu$ F. For example,

50,000 meg $\Omega \mu F$ = 500 meg $\Omega \times 100 \mu F$ or = 5,000 meg $\Omega \times 10 \mu F$ etc.

To find the IR for a capacitor, divide "meg $\Omega\mu$ F" value by " μ F." For example, if the manufacturer specifies 1000 meg $\Omega\mu$ F and you have a 0.47 μ F capacitor then the IR limit will be:

$$\frac{1000 \operatorname{meg} \Omega \mu F}{0.47 \ \mu F} = 2127 \operatorname{meg} \Omega$$

For a 0.015 μ F capacitor, the IR limit would be:

$$\frac{1000 \text{ meg } \Omega \mu F}{0.015 \ \mu F} = 66,666 \text{ meg } \Omega$$

Sometimes the use of a limiting value along with the IR constant causes some confusion. This became necessary with the advent of plastic film capacitors because their high inherent IR and very small capacitance ratings required instruments that could measure in the millions of megohm range.

So, manufacturers also specify a maximum IR limit. For example, though a 0.005 μ F capacitor

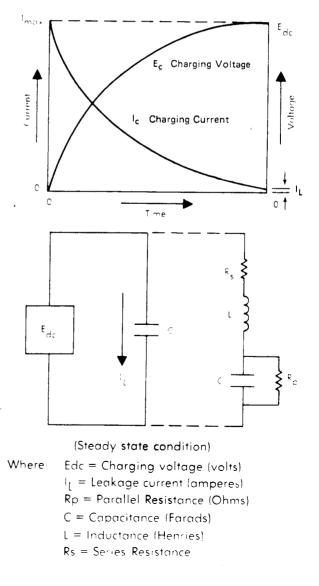
would have an IR of 200,000 meg Ω (if specified at 1000 meg $\Omega\mu$ F), manufacturer's specifications typically state "need not exceed 100,000 meg Ω ."

As noted earlier, each dielectric material has its own inherent insulation resistance which depends on the chemical and molecular structure composition of the material.

Ceramic dielectrics have two classes of matrial – Type 1 and II. Type 1 ceramic (includes COG dielectric) is the best, being 100K meg Ω maximum or 1000 meg $\Omega \propto \mu$ F, whichever is less. X7R, a stable material, is typically the same even though it's Type II. However, Z5U is typically 10K meg Ω maximum or 500 meg $\Omega \propto \mu$ F, whichever is less.

Since manufacturers' specified IR values differ, we recommend that you check the specification for the particular capacitor you are going to use.

For more details, call Harry Ford, Component Engineering (58-299), ext. 6520.



Freon contaminates electrolytic capacitors

It has been observed, both here at Tektronix and elsewhere, that Freon[®] contamination of aluminum electrolytic capacitors results in early component failure:

While we haven't established what reactions take place, or exactly which of the components – Freon, electrolyte, aluminum foil, aluminum oxide – are involved, we have established some criteria for differentiating Freon-caused failures from other failure mechanisms.

electrical potential must be present

Freon is a particularly stable compound, and under normal conditions, is completely inert. The halogen atoms are tightly bound to the Freon molecule and without adding energy to the system, no reaction will take place.

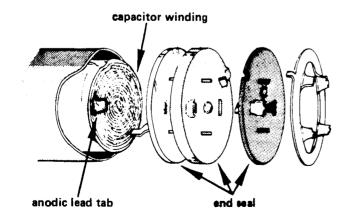
When a dc voltage is impressed across the capacitor, however, the Freon molecule is torn apart. The resulting free ions then migrate toward the anodic foil and attack it.

what to look for

The technician will observe an intermittant or open circuit in a capacitor that is suffering from Freon damage. Because there is no reaction without applied voltage, Freon contamination cannot be detected on parts from stock or on boards in production. But, parts in instruments which have gone through precalibration and cycling (40-50 hours of operation) should give indications of Freon damage.

what we find

In Freon-damaged capacitors we observe large pitted areas, or holes, in the anodic foil. In addition, a dark grey residue is present, usually around the



Cutaway view of Freon-damaged capacitor.

anodic lead tab in paste or crystalline powder depending on whether or not there's any electrolyte left.

In an undamaged electrolytic capacitor, the paper spacer between the anodic and cathodic foils is not bound to the foil in any way. Therefore, the spacer and foil are easily separated when the capacitor is unwound. When there is corrosion from Freon damage, the paper sticks to the foil as if glued.

The longer the part has been in use, the easier it is to recognize the effects of Freon damage. For this reason, for parts that have seen only a few days of operation, it's particularly helpful to know how the part was mounted on the equipment. Most of the electrolyte, and therefore the Freon, will pool towards the bottom of the capacitor. This is where we can most likely expect to find damage.

In summary, the following procedure should be followed:

1. Be sure the capacitor has been operating for at least two days.

2. If possible, determine the position that the capacitor was in during operation.

3. Any capacitor suspected of being damaged by Freon should be replaced and returned to Component Reliability Engineering.

If you are going to be taking the capacitor apart yourself:

1. Open it and inspect for pitting of the anodic foil, concentrating on the suspect area.

2. Look for a dark grey paste or crystalline deposit.

3. Look for areas where the paper spacer sticks to the anodic foil.

For further help, please contact Larry Meneghin, Component Reliability Engineering, at delivery station 58-176, or call ext. 7268.

Correction

Issue 254 of **Component News** incorrectly reported a part number for a redesigned, Tekmade knob (see page 5). The part number listed as 366-1619-03 should be 366-1519-03.

Contact Harvey Gjesdal (ext. 7791) for more details.

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New Series 73 ModPot proposed

Allen-Bradley ModPots® are a versatile family of front panel controls which have become widely used in Tek products in recent years. The original Series 70 version used a machined bushing and faceplate, making it a fairly expensive component. In an effort to lower cost A-B introduced two additional versions.

The Series 72 is an all-plastic one- or two-section component especially attractive for certain high voltage applications. Because it is very limited as to shaft and switch combinations, we've assigned only four or five new part numbers. In this case, substitution of molded plastic parts for machined parts and screws decreases cost by about 20%.

The second version, Series 73, uses a machined metal bushing and mounting surface, insert-molded into a plastic faceplate. Because the machined part is smaller and requires no secondary operations, a cost savings of 5 to 15% is realized, even though metal shafts (including concentric) are available. We've begun using these devices in substantial quantities, in both new and existing part numbers.

Series 73 pots for bushing mounting are limited to single and dual assemblies by the strength of the two-piece bushing/faceplate (we use some 73 triples, but they are ECB mounted). To meet the need for a low-cost design sufficiently strong for triples and quads, A-B proposes use of a die-cast zinc alloy bushing plate. Parts which are one and two sections long will use a cast alloy rear plate, with studs which are swaged over as they emerge through the small holes in the bushing plate. Triples and quads will use the conventional plastic rear cover, and screws. Alloy material is Zamac 3; plating is dull nickel. Samples passed the 10-day humidity exposure with corrosion confined to the swaged areas. There is some concern that the large area of metal, appearing where previously there were only plastic and four small screw heads, could cause problems. The possibility exists that new UL requirements would be more difficult to meet with the new parts.

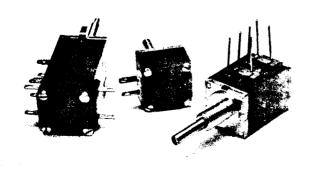
I'm asking that all staff engineers whose products use ModPots examine the effects of the modifications just discussed. Please let me know your conclusions.

If you wish, I can supply a few samples for your inspection, but samples in your particular part number will take six to eight weeks. Your concerns will be discussed with the vendorespecially those involving safety. Gene Single

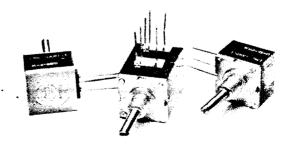
Component Engineering (ext. 5302)



Present Series 73 ModPots. Single-section controls use swaged-over plastic prongs to hold the parts together; duals use screws. Note faceplate construction.



Series 70 ModPots. All use machined bushing/faceplate and four, #1-64 screws.



Proposed Series 73 ModPots. Both singles and duals will use swaged-over metal prongs; triples and quads will look like the Series 70 (screws and plastic rear cover) except for the die-cast bushing plate.

Microprocessor

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Crystals

The following is a list of microprocessor crystals, some of which are part numbered at Tektronix. These crystals feature a low start-up resistance and are ideal for use with micro-processors. For more information, contact Byron Witt in Component Engineering, ext. 5417.

| (MHz) | μP vendor | Microprocessor | Tek P/N |
|--------------------|--------------------|----------------------------------|-------------|
| 1.000 | Motorola | 6800 | 158-0025-00 |
| | AMI | S6800 | 158-0025-00 |
| | National | SC/MP | |
| | RCA | COP1800/1802 | |
| 1.025 | Signetics | 2650 | |
| 1.8432 | Motorola | MC14410 Baud Rate Generator | |
| 2.000 | Fairchild | F-8/CPU 3850 | 158-0070-00 |
| 2.012 | | Special for MPU's | |
| 2.097152 | Mostek | MM5378/5379 | |
| 2.4576 | Fairchild | 34702 Bit Rate Generator | 158-0124-00 |
| 2.50 | Intersil • | IM6100 | 130-0124-00 |
| 3.000 | TI | TMS9900 | 158-0126-00 |
| 3.2768 | Intersil | ICM7205 | 158-0120-00 |
| 3.33 | Intersil | IM6102 | |
| 3.579545 | 111(013) | Special for MPU's | 158 0105 00 |
| 3.595325 | | Special for MPU's | 158-0105-00 |
| 3.93216 | | Special for MPU's | |
| 4.000 | Intel | | |
| 4.000 | | 4040/4004/4201 | 158-0056-00 |
| | Harris National | HM6100 | |
| | | Pace IPC16 | |
| | Intersil | IM6100, IM6102 | |
| 4.434 | Signetics | 2650 | 158-0075-00 |
| 4.44 | | Special for MPU's | |
| 4.55 | Intel | 4040/4004/4201 | |
| 4.75 | Intel | 4040/4004/4201 | |
| 4.9152 | | Special for MPU's | 158-0072-00 |
| 4.9562 | Intel | 4040/4004/4201 | |
| 5.000 | TI | TMS, Special for MPU's | 158-0084-00 |
| 5.0688 | SMC | Com 5016/5016T Dual Baud | |
| | | Rate Generator | |
| 5.185 | Intel | 4040/4004/4201 | |
| 5.333 | | Special for MPU's | |
| 5.585 | Intel | 4040/4004/4201 | |
| 5.587 | Intel | 4040/4004/4201 | |
| 5.7143 | National | Pace | |
| 6.000 | GI | CP1600 | |
| | Intel | 8748 | |
| 6,144 | Intel | 8085 | |
| 6.5536 | Intersil | ICM7045 | |
| 6.666 | inter an | Special for MPU's | |
| B.000 | GI | CP1600 | |
| 0.000 | Intersil | IM6100 | |
| 8.448 | mersn | Special for MPU's | |
| 9.8304 | | Special for MPU's | |
| 10.000 | GI | CP1600A, Special for MPU's | 158-0031-01 |
| 11.430 | | Special for MPU's | 100-0031-01 |
| 12.000 | | Special for MPU's | |
| 13.5168 | Intel | 8080/8008/8224 | |
| 14.31818 | Intel | 8080/8008/8224 | |
| 15.000 | Intel | 8080/8008/8224 8080/8008/8224 | |
| | 111(61 | Special for MPU's | |
| 16 69990 | | | |
| 16.58880 18.000 | Intel | 8080/8008/8224 | |

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| (MHz) | μP vendor | Microprocessor | Tek P/N |
|----------|-----------|-------------------|-------------|
| 18.432 | Intel | 8080/8008/8224 | 158-0136-00 |
| 19.354 | Intel | 8080/8008/8224 | 158-0130-00 |
| 19.6608 | Intel | 8080/8008/8224 | |
| 20.000 | | Special for MPU's | 158-0154-00 |
| 22.032 🕺 | | Special for MPU's | 100 0104 00 |
| 22.1184 | Intel | 8080/A | |
| 23.400 | Intel | 8080/8008/8224 | |
| 23.684 | Intel | 8080/8008/8224 | |
| 24.576 | Intel | 8080/8008/8224 | |
| 25.000 | Intel | 3000 | 158-0077-00 |
| 27.000 | Intel | 8080/8008/8224 | 100-0077-00 |
| 28.1250 | | Special for MPU's | |
| 32.000 | Intel | 8080/8008/8224 | |
| 36.000 | AMD | Special for MPU's | |
| 48.000 | TI | TMS9900 | 158-0152-00 |
| 100.00 | Fairchild | Special for MPU's | 158-0106-00 |
| | | | 158-0108-00 |

1 MW. Temperature tolerance is $\pm 0.01\%$ from 0 to 70°C. Series resistance varies with frequency. Shunt capacitance is 32 pF.

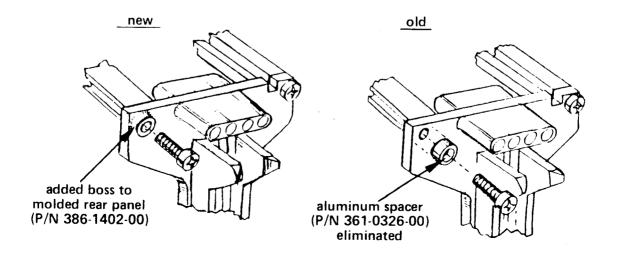
Rear panel design modified

The upper right-hand screw on the rear panel previously needed an aluminum spacer mounted under it to allow the screw head to protrude and make contact with a ground clip. This spacer (P/N 361-0326-00, 3ϕ each, annual usage 50,000+) has been eliminated in the modified rear plastic panel (P/N 386-1402-00) by having a boss molded into the plastic to extend the screw head. The

screw itself remains the same and all old stock is being used up first.

Double-wide plug-ins are not affected and will continue to use the spacer.

For more information, please contact Harvey Gjesdal, Lab Oscilloscope Products Evaluation, ext. 7791.



High-frequency dual FET part numbered

A monolithic matched dual DMOS FET transistor has been part numbered at Tek: 151-1117-00. This DMOS part is now our highest frequency dual FET.

Typical parameter values (measured at 15V, 10 mA) are: $g_m = 16$ mmho, CGS = 3.6 pF, CDG = 1.07 pF. The device is specified for an offset voltage of 25 mV maximum, and 25 μ V/°C drift.

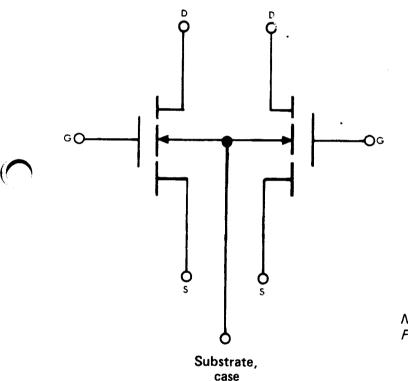
Zero TC occurs at about 5 mA where the g_m is still nearly 10 mmhos. Drain currents of up to 70 mA per side can be produced, with the g_m maximizing at about 65 mA.

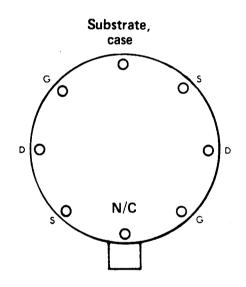
The f_{T} is 500 MHz at 5 mA, rising to 790 MHz at 60 mA.

• • •

The part is an N-channel, enhancement mode device in a TO-99 case with the pin-out as shown below. Note that the common substrate does not allow totem-pole operation.

For more details, contact Jerry Willard, Analog Component Engineering, ext. 7461.





Note that the pinout is the same as other dual FETs, and that the gates are not zener protected.

DMAC samples here

Two samples of MC6844 Direct Memory Access Controller (DMAC) are available in Component Engineering for product-related development projects.

For more information, please contact Jim Howe, ext. 5698.

New product information

The UCN-4401A and UCN-4801A latch/ drivers are a combination of four or eight CMOS latches with a bipolar Darlington transistor driver for each latch. These are new products from Sprague.

The open collector drivers can sink up to 500mA each, or can sustain at least 50 volts in the off state.

Moisture-vapor barrier reduces condensation

It was recently brought to our attention in Packaging Design, that 100% of a particular product line being shipped to points in Texas and Florida arrived with water condensation damage.

We determined that the problem was caused by temperature changes encountered while being trucked over the mountains. Products shipped by air suffered no such damage. Clearly, the thin polyethylene bag then being used did not provide sufficient moisture protection.

Subsequent testing indicates that Champion "Foil-Rap 2175" (which conforms to military specification MIL-B-131, Class 1) would provide an acceptable vapor barrier for. packaging Tek products at a fairly low cost. A 24" x 36" bag made from this material costs \$1.18 in quantities of 1000.

For heavier items, another material with similar properties (conforming to military specification MIL-C-9959) is available. Sold as complete package assemblies, these units are initially very expensive, but they are re-usable, so that their cost could be spread out over a number of instruments.

Dessicant (a moisture absorbing material) is used inside these moisture-vapor barriers to absorb the small amount of moisture that does penetrate the barrier. The amount, and therefore the cost, of the dessicant needed depends on the size of the instrument and what is packed in the barrier bag along with the instrument. The dessicant used for the USM 425 costs approximately 65ϕ .

For more information on moisture-vapor barriers please contact Paul Phelps, ext. 7615.

2102 reliability tests

Reliability testing on a 2102 1K x 1 RAM (Tek P/N 156-0291-00) has been completed for two vendors: Intel and Signetics.

Fifty parts from each vendor were tested for 96 hours. The ambient temperature was 125°C and the power supply was set at nominal value. Alternating ones and zeros were read from and written into each cell.

The life test results were as follows:

| | No. of failures at | | | | | | | |
|-----------|--------------------|---------|---------|---------|--|--|--|--|
| Vendor | 0 hrs. | 16 hrs. | 36 hrs. | 96 hrs. | | | | |
| Signetics | 2 | 0 | 0 | 0 | | | | |
| Intel | 0 | 0 | 0 | 1 | | | | |

Based on the result of the life test, we do not feel that burn-in is necessary with this part. We do recommend, however, 100% electrical testing before use (use the 156-0291-01, 100% tested version).

For more details, contact Steve Hui in Component Reliability Engineering, ext. 6511.

DIP caps feature 0.3" lead spacing

AVX has introduced a series of DIP capacitors featuring 0.3" lead spacing. These epoxy cased caps offer several advantages over the more conventional, axial-leaded packages.

The new package design makes the capacitors easily hand-insertable, with the capability of being machine-inserted. Pre-formed leads eliminates lead-cutting and bending.

The parts are mechanically superior to glass, axial leaded caps. In addition, the AVX design helps remove the dips and bumps in the path of the air flow across the board.

The following versions of this capacitor are Tek part numbered:

| value | temp. char. | <u>Tek P/N</u> | |
|---------------|-------------------------------|--|--|
| 0.22 µF, 50∨ | Z 5U | 283-0423-00 | $ \cap$ |
| 0.047 µF, 50∨ | Z5U | 283-0422-00 | Y K |
| 0.10 µF, 50∨ | Z5U | 283-0421-00 | \sum |
| | 0.22 μF, 50V 0.047 μF, 50V | 0.22 μF, 50V Z5U 0.047 μF, 50V Z5U | 0.22 μF, 50V Z5U 283-0423-00 0.047 μF, 50V Z5U 283-0422-00 |



Reliability report: Plastic vs. metal can transistors

Several design engineers have requested information on the relative reliability of plastic encapsulated versus metal can transistors. We have calculated projected failure rates for a T0-92 (151-0190-00) versus an equivalent T0-18 part (151-0190-06 or 151-0460-00) for several different power levels.

This calculation shows that the metal can parts should exhibit a somewhat lower failure rate than the plastic parts (based on failure rate projection concepts presented in **Component News** No. 255). See table below.

Metal Can vs. Plastic Comparison

Assumptions:

5% Freaks 30°C ambient, 20°C internal rise in instrument $\theta_{JA} \approx 230^{\circ}$ C/watt for plastic 300°C/watt for metal can

| | | Plastic 151-0190-00 |) | | Metal can 151-0190-06 | 5 |
|---|-------|------------------------|------------|-------|--------------------------|-------|
| Power level | 50mW | 100mW | 200mW | 50mW | 100mW | 200mW |
| ∆⊤ _j , °C | 11 . | 23 | 46 | 15 | 30 | 60 |
| T _j , actual, °C | 61 | 73 | 96 | 65 | 80 | 110 |
| Failure rate W/F*, %/1000 hrs. | 0.08 | 0.3 | 3 | <0.01 | 0.06 | 0.8 |
| Failure rate W/OF ** | <0.01 | <0.01 | 0.3 | ≪0.01 | <0.01 | <0.01 |
| with freaks (raw parts, electrically 1 ** without freaks, i.e., freaks removed | | llowed by elect | rical test | | | |

The thermal resistance (junction to ambient) is slightly lower for the plastic cased unit, leading to lower junction temperatures for a given power dissipation. However, projected failure rates for the plastic parts are higher because they have a shorter freak and main population life when both are referenced to the same temperature.

Also shown in the table is the effect of a 100% burn-in on the projected failure rate.

For more information contact Ron Schwartz, ext. 6511.

Sample tests or 100% burn-in for transistors

The article on transistor burn-in in **Component News** No. 255 described two approaches being pursued by Component Reliability Engineering for transistor reliability enhancement.

Reliability sample test requirements are being applied to most high-usage bipolar transistor specifications to establish minimum levels of reliability for vendor qualification and new part lot acceptance criteria. These requirements are designed to assure a maximum failure rate of 0.1%/1000 hours at 70°C junction temperature for plastic encapsulated parts.

If failure rates of much lower than 0.1%/1000 hours are necessary to meet instrument reliability goals, 100% burn-in is necessary. By removing freaks with a high temperature burn-in, failure rates of 0.01%/ 1000 hours or lower can be achieved.

For more details, contact Ron Schwartz, ext. 6511.

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APPENDIX A: Reprinted from Component News 255, p. 19 (with additions)

| Part Number | Vendor | Qualified? | Freak% | Part Number | Vendor | Qualified? | Freak% |
|----------------------------|--|-------------------|----------------------------|---|---|--------------------------|------------------------------|
| 151-0103-00 | Motorola Fairchild T.I. | yes yes | 8 20 12 | 151-0279-00/01 | Fairchild Motorola National T.I. | yes yes yes yes | (25) (25) (12) (25) |
| 151-0126-00 | Motorola National Fairchild | 0 0 0 | < 4 < 4 < 4 | 151-0289-00 | Motorola | yes | 25 |
| | Teledyne | no | <4 | 151-0333-00 | Motorola | yes | < 4 |
| 151-0127-00 | Raytheon Motorola | yes Q | <4 <2 | 151-0341-00 | National | yes | < 4 |
| 101 012/-00 | Fairchild | yes | <2 | 151-0342-00 | National Fairchild | yes yes | < 4 4 |
| 151-0150-00 151-0188-00 | Motorola Fairchild RCA Motorola | yes yes yes | (10) (10) 40 (20) | 151-0347-00 | Motorola Fairchild National NPC | yes yes yes Q | 6 12 50 < 3 |
| 454 0400 00 | T.I. National | yes • yes | (10) (7) | 151-0350-00 | Sprague T.I. Fairchild | Q yes** yes | 11 62 10 |
| 151-0190-00 | Motorola Sprague | yes Q | < 2 8 | 151-0358-00 | G.E. | ves | 5 |
| 151-0190-06 | T.I. Motorola | yes Q | (25) < 4* | 151-0423-00 | Fairchild T.I. | yes no | < 2 45 |
| (151-0460-00) | т.І. | yes | < 2 | 151-0425-00 | Motorola | yes | 8 |
| 151-0195-00 | Motorola | yes | < 4 | 151-0426-00 | G.E. | yes | <2 |
| 151-0199-00 | Motorola | yes | 15 | 151-0427-00 | National | yes | 11 |
| 151-0216-00 | Motorola T.I. | yes yes | <2 <2 | 151-0435-00 | Motorola Fairchild | yes no | (15) 100 |
| 151-0220-00 | Fairchild | yes | (12) | 151-0443-00 | Motorola | yes | (15) |
| 151-0225-00 | Teledyne National | yes ** yes | 100 12 | 151-0451-00 | RCA SSS | γes | 19 15 |
| 151-0228-00 | Fairchild | yes | 25 | 151-0462-00 | т.і. | no | 40 |
| 151-0250-00 | Fairchild | yes | 12 | · | RCA Motorola | yes Q | 20 < 5 |
| 151-0254-00 | G.E. National | yes Q | 89 4 | | Fairchild National | Q | 5 < 5 |
| 151-0259-00 | Fairchild | yes | 4 | 151-0478-00 | T.1. | yes | 15 |
| 151-0260-00 | Motorola T.I. SSS | yes yes no | 4 4 20 | | RCA Motorola | yes | < 5 < 5 |
| 151-0270-00 | Fairchild T.I. | yes yes | 6 10 | (x) indicates freak Q in qualification * metal can vers | process | | n stress level. |

**CRE has recommended disqualification on this part/vendor

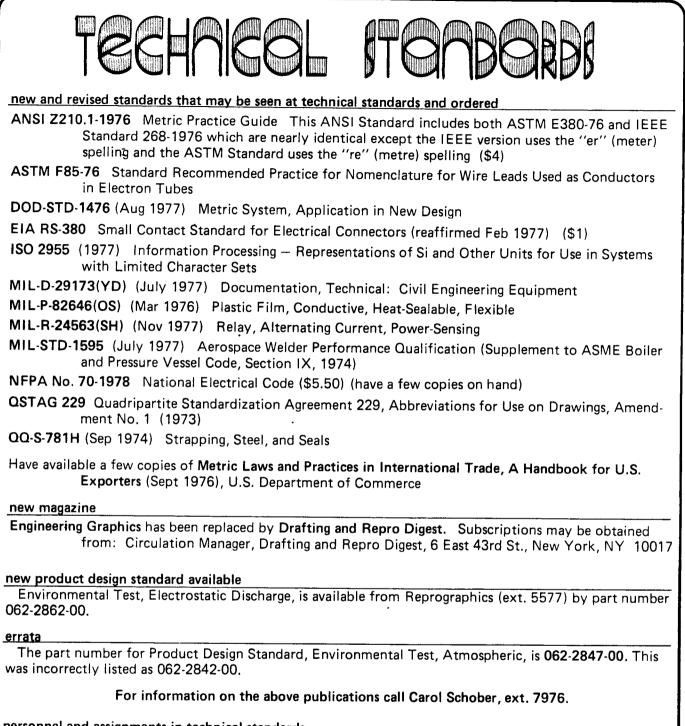
Errata from Component News 255

Page 13 E_A = activation energy in eV (1.0 eV is used in our calculations)

Page 15 (bottom) $80^{\circ}C \sim 1430$

Page 21 with burn-in < 0.1%

with burn-in < 0.01%



personnel and assignments in technical standards

We welcome **Roy Eckelman** and **Carol Jones** to our group. Roy is replacing Laon Lingel and will work on standards for cables, drafting, fabrication, occupational safety, and product safety. Roy can be reached at ext. 7451.

Carol's assignments include cables, color, documentation, finish, and test methods. She will also be involved with circuit boards and some product design standards. Her extension is 6224.

Dwain Hall is primarily involved with circuit board and product design standards, ext. 6823.

Carol Schober should be contacted for information on Tektronix standards and external standards such as industry, military, and international. She can be reached at ext. 7976.

Pauline Whitmore will provide information on component mounting details and the Standards Directory, ext. 5136.

Chuck Sullivan Technical Standards manager Page 18 of 22

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COMPONENT NEWS 256

COMPONENT CHECKLIST

The "Component Checklist" is intended to draw attention to problems or changes that affect circuit design. This listing includes: catalog and spec changes or discrepancies; availability and price changes; production problems; design recommendations; and notification of when and how problems were solved. For those problems of a continuing nature, periodic reminders with additional details will be included as needed.

| Tek P/N | Vendor | Description of Part | Who to contact | | | |
|---------------------------------|--|---|--|--|--|--|
| 156-0877-00 | 8251. The A version | 8251 USART 56-0877-00 are being char on is compatible with the c of the data sheet call me a | original 8251 and has seve | eral design bugs cor- | | |
| 156-1017-00 | EPROMs, please re | 2716 EPROM Bob Goe billity problems, we request that once you are finished using 156-10 return them to stock, so that other designers need not experience u caining these devices. | | | | |
| 156-1088-00 | 0 Intel 8085A microprocessor A problem has been discovered in the most recent version o The trap flag of the 8085A remains high after a power on re interrupt of the processor following the reset signal. The pro execution at the TRAP address instead of at address zero. | | | et. This causes an immediate | | |
| | econd reset pulse. The | | | | | |
| | Intel hopes to hav | input works correctly once the trap flag has been cleared. hopes to have a new version of the 8085A ready in March. Production quantities d be available in June. | | | | |
| no P/N | | Data I/O PROM program I/O PROM programmer, y . Call Bob, ext. 6302 to rea | ou may be interested in t | Bob Goetz, 6302 wo field bulletins | | |
| (see list) | 0.150 min., 0.190 | ceramic capacitors, axial the capacitors listed below max. (dia. 0.090 ± 0.01). Nelivering parts with the sho | are being revised to chan We will have to live with r | mixed stock until | | |
| 281 281 281 281 281 | -0757-00 -0758-00 -0759-00 -0762-00 -0763-00 -0764-00 | 281-0765-00 281-0767-00 281-0768-00 281-0769-00 281-0770-00 281-0785-00 | 281-0786-00 281-0788-00 281-0791-00 281-0792-00 281-0797-00 281-0798-00 | 281-0799-00 281-0809-00 281-0812-00 281-0814-00 | | |

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JomponentNewsNewComponents

This column is designed to provide timely information regarding new components, vendors, availability and price. "New Components" can also be used as an informal update to the Common Design Parts Catalogs. Samples may or may not be available in Engineering Stock.

| Vendor | <u>-</u> No. | Description | W availa | hen able Tek P/N | Appro cost | - |
|-----------|--------------|--|-------------|---------------------|---------------|------------------------|
| | | analog devi | ices | | | |
| тι | TL072CP | Op amp, dual, JFET-input | now | 156-1191-00 | \$.71 | John Hereford, 6700 |
| TI | TL074CN | Op amp, quad, JFET-input | now | 156-1200-00 | 1.25 | John Hereford, 6700 |
| Fairchild | FT317A | Power transistor, NPN 120V, VCEO(sus), IC = 4A, 40W, TO-220 pkg, fT = 20 MHz (complement to 151-0647-00) | Mar. | 151-0674-00 | .85 | Jim Williamson, 5345 |
| Motorola | MJE13005 | Power transistor, 400V, V _{CEO} (sus), I _C = 4A, PD = 75W, TO-220 pkg, fT = 4 MHz ''switchmode'' | Mar. | | .74 | Jim Williamson, 5345 |
| | | digital devi | ces | | | |
| TI, Mot. | 74LS122 | Retriggerable one-shot | soon | no P/N yet | | Wilton Hart, 7607 |
| Nippon | SM8550 | Floppy disk controller | now | no P/N yet | | Wilton Hart, 7607 |
| MMI, AMD | 74S240 | Octal buffer | now | no P/N yet | 1.75 | Dave Sutherland, 6301 |
| MMI, AMD | 74S241 | Octal buffer | now | 156-1179-00 | 1.75 | Dave Sutherland, 6301 |
| MMI, AMD | 74S244 | Octal buffer | now | no P/N yet | 1.75 | Dave Sutherland, 6301 |
| Signetics | 82S185 | 2K × 4 PROM | now | 156-1182-00 | | Dave Sutherland, 6301 |
| ΓI | 74S197 | Binary counter | now | 156-1183-00 | | Dave Sutherland, 6301 |
| TI | 74S189 | 16 × 4 RAM | now | 156-1189-00 | 1.25 | Dave Sutherland, 6301 |
| τI | 74S138 | 3 to 8 line decoder | now | 156-1194-00 | | Dave Sutherland, 6301 |
| AMD | 26S02 | Dual monostable multivibrator | now | 156-1195-00 | ••• | Dave Sutherland, 6301 |
| TI | 74S181 | Arithmetic logic unit | now | 156-1196-00 | | Dave Sutherland, 6301 |
| TI | 74S299 | 8-bit shift register | now | 156-1197-00 | — | Dave Sutherland, 6301 |
| TI | 74S163 | Synchronous 4-bit counter | now | 156-1198-00 | | Dave Sutherland, 6301 |
| | | electromechanica | l devic | es | | |
| TI | | Hall effect switch on 17.5 mm film | Ίyr. | | .40 | Joe Joncas, 6365 |
| ΓI | | Hall effect switch on 17.5 TO-226AA | now | | .35 | Joe Joncas, 6365 |
| | | Machine screw 2-56 x 0.156L, PNH, SST, POZ | now | 211-0264-00 | .01 | Rod Christiansen, 5953 |
| | | Washer, Teflon, 0.45 I.D. x 1.1 O.D. x .01 TK. | now | 210-1284-00 | .20 | Rod Christiansen, 5953 |
| <u></u> | | Washer, split lock #10, 0.048 Tk Cd. plated steel | now | 210-0081-00 | .05 | Rod Christiansen, 5953 |
| | | Cap screw, 5-40 x 0.5 skt hd, Cd. plated | now | 211-0270-00 | , .05 , | Rod Christiansen, 5953 |
| | | Cap screw, 2-56 x 0.125 skt hd SST | now | 211-0266-00 | .04 | Rod Christiansen, 5953 |
| | | Cap screw, 2-56 x 0.375 skt hd, SST | now | 211-0265-00 | .05 | Rod Christiansen, 5953 |
| | | Cap screw, 2-56 x 0.75 skt hd, SST | now | 211-0263-00 | .09 | Rod Christiansen, 5953 |
| | | Thread forming screw, 8-32 x 0.312 fl hd, TT, Cd plated steel, Posidriv | now | 213-0801-00 | .02 | Rod Christiansen, 5953 |
| | | Set screw, 4-40 x 0.5 hex skt, SST, cup pt | now | 213-0791-00 | .10 | Rod Christiansen, 5953 |
| | | | 0014 | 010 0000 00 | .02 | Rod Christiansen, 5953 |
| <u></u> | | Set screw, 4-40 x 0.25 hex skt, Cd plated steel | now | 213-0800-00 | .02 | noo onistiansen, 5953 |
| | | | now | 213-0800-00 | .02 | Rod Christiansen, 5953 |

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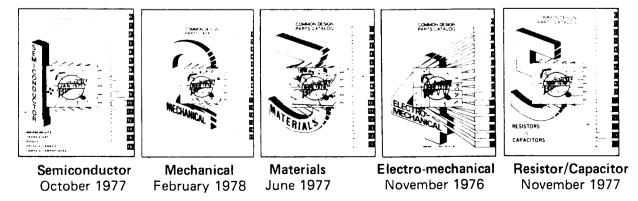
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continued from page 19

| Vendor No. | | Description | W availa | hen able | Tek P/N | Appro cost | x. Engineer to contact |
|-----------------------------|--------------|---|-------------|-------------|---------|---------------|---------------------------|
| | | resistor, capacitor, optoelectronic devices | | | | | |
| capacitor, fi | xed | | | | | | |
| Mallory,Spra | ague . | $10\mu F \pm 5\%$, 20V solid tant., herm. sealed | now | 290- | 0830-00 | .21 | Merle Hendricks, 5415 |
| United Cher Matsushita, | | 1µF, 250V aluminum axial lead | now | 290- | 0763-00 | .09 | Merle Hendricks, 5415 |
| United Cher Matsushita | n.,Nichicon, | Min-aluminum single ended | now | 290- | 0831-00 | | Merle Hendricks, 5415 |
| Electrocube Electronic C | • | $0.047 \mu F$, 600V metallized mylar | now | 285- | 1170-00 | | Merle Hendricks, 5415 |
| resistor, fixe | d | | | | | | |
| A-B | BB1005 | 10 $\Omega\pm$ 5% 1/8 W | Feb. | 317- | 0100-03 | .08 | Ray Powell, 6520 |
| A-B | BB1015 | $100\Omega\pm5\%$ 1/8W | | | 0101-01 | .08 | Ray Powell, 6520 |
| A-B | BB2005 | $20\Omega \pm 5\%$ 1/8W | | | 0200-03 | .08 | Ray Powell, 6520 |
| A-B | BB2205 | $22\Omega\pm5\%$ 1/8W | | | 0230-03 | .08 | Ray Powell, 6520 |
| A-B | BB2705 | 27 $\Omega\pm$ 5% 1/8W | | | 0270-03 | .08 | Ray Powell, 6520 |
| A-B | BB3005 | $30\Omega\pm5\%$ 1/8W | | | 0300-03 | .08 | Ray Powell, 6520 |
| A-B | BB3605 | $36\Omega\pm5\%$ 1/8W | | | 0360-03 | .08 | Ray Powell, 6520 |
| A-B | BB4305 | $43\Omega\pm5\%$ 1/8W | Feb. | 317- | 0430-03 | ,08 | Ray Powell, 6520 |
| A-B | BB4315 | 430 $\Omega\pm$ 5% 1/8 W | | | 0431-03 | .08 | Ray Powell, 6520 |
| A-B | BB4705 | 47 $\Omega\pm$ 5% 1/8W \cdot | Feb. | 317- | 0470-03 | .08 | Ray Powell, 6520 |
| A-B | BB4715 | 470 $\Omega\pm$ 5% 1/8W | Feb. | 317- | 0471-03 | .08 | Ray Powell, 6520 |
| A-B | BB5105 | 51 $\Omega\pm$ 5% 1/8W | Feb. | 317- | 0510-03 | .08 | Ray Powell, 6520 |
| A-B | BB5605 | 56 $\Omega\pm$ 5% 1/8W | Feb. | 317- | 0560-03 | .08 | Ray Powell, 6520 |
| A·B | BB6205 | $62\Omega\pm5\%$ 1/8W | Feb. | 317- | 0620-03 | .08 | Ray Powell, 6520 |
| A-B | BB6805 | $68\Omega \pm 5\%$ 1/8W | Feb. | 317- | 0680-03 | .08 | Ray Powell, 6520 |
| A-B | BB7505 | $75\Omega \pm 5\%$ 1/8W | | | 0750-03 | .08 | Ray Powell, 6520 |
| A-B | BB9105 | 91 $\Omega\pm$ 5% 1/8W | Feb. | 317- | 0910-03 | .08 | Ray Powell, 6520 |
| Dale,Mepco,Electra | | 1.96M Ω ± 1% TO 1/8W | Mar. | 321- | 0509-00 | .08 | Ray Powell, 6520 |
| Dale,RCL,Kelvin | | $2\Omega\pm5\%$ 5W | Mar. | 308- | 0119-00 | .15 | Ray Powell, 6520 |
| Dale,RCL | NS1015000 | $1.5K \pm 2\%$ non-inductive, 10W | Feb. | 308- | 0809-00 | .40 | Ray Powell, 6520 |
| Dale,IRC | MFF1816G | $1.21M\Omega \pm 1\% 1/8W$ | Feb. | 321- | 0489-00 | .05 | Ray Powell, 6520 |
| Dale,Mepco | MFF1226G | 255 $\Omega\pm$ 1% 1/2W | Feb. | 323- | 0136-00 | .04 | Ray Powell, 6520 |
| Corning | · | 1.5K ± 10% 3W | Feb. | 307- | 0616-00 | .14 | Ray Powell, 6520 |
| A-B | GB3305 | $33\Omega\pm5\%$ 1W | Feb. | 307- | 0330-00 | .08 | Ray Powell, 6520 |

PARTS CATALOG NOTICE

The following Common Design Parts Catalogs are currently available from the Catalogs group:

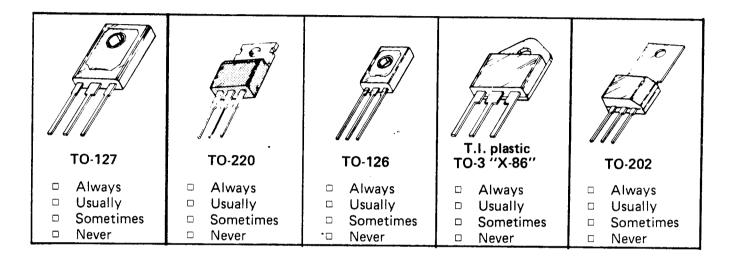


Contact Fred Schade (58-276), ext. 7974, to receive any of these catalogs.

Plastic transistor mounting survey

In an effort to standardize transistor mounting techniques, we are asking people who use power transistors to complete the following questionnaire. Please send the completed form to Jim Williamson (58-299).

1. Which transistor plastic package styles do you use?



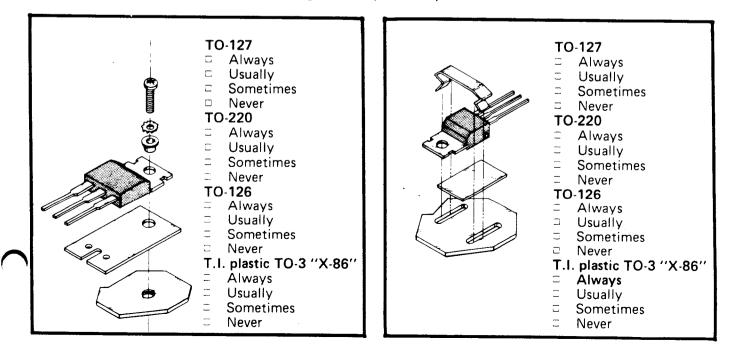
2. Which insulating materials do you use?

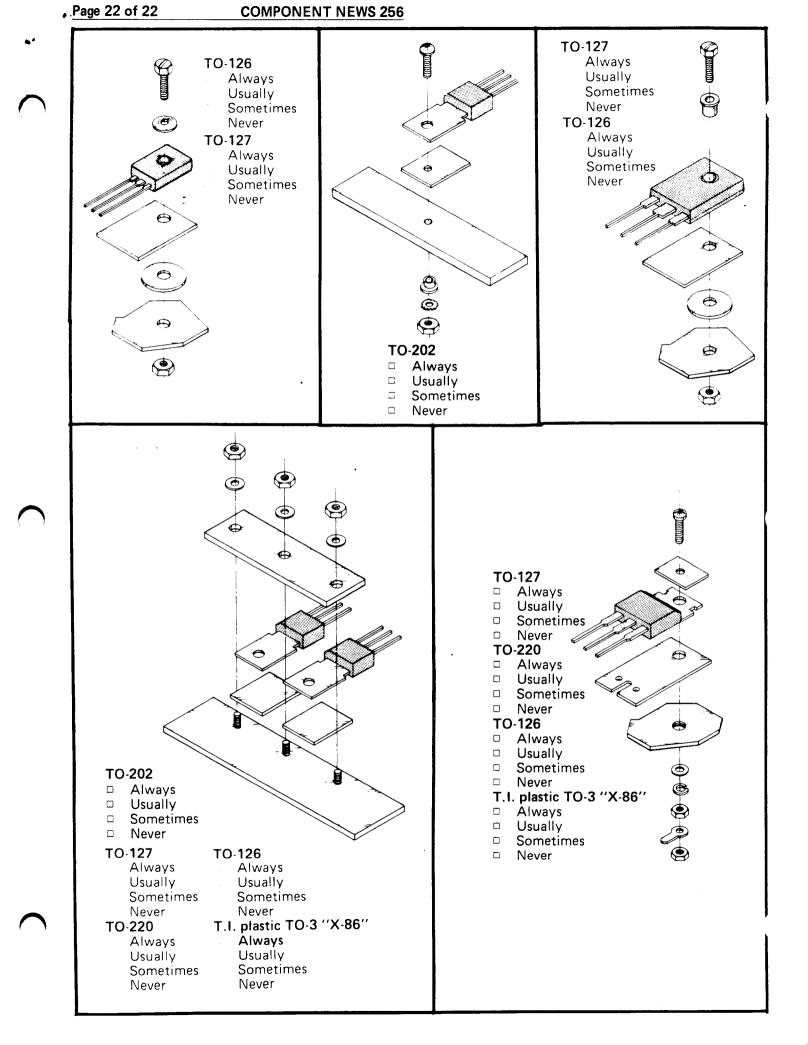
mica □ Kapton/thermal film _□ (orange plastic)

Silicon Rubber D

Beryllium Oxide (BeO) Annodized Aluminum Other (specify)

3. Which transistor mounting techniques do you use?





PRODUCT SAFETY NOTE NO. 31A

18 January 1978

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Subject: Primary-wire breakage.

In Item 2 of Product Safety Note No. 31, we referred to breakage of internal primary wires at the points of connection.

Product Safety Note No. 31 mentions two ways of dealing with wire breakage--a clamp as close as practicable to the conductor ends, and alternatively, cable lacing that terminates as close as practicable to the conductor ends.

Actually, there are probably many ways of handling this problem. A third means that has been brought to our attention consists of placing sleeving over the primary-circuit wires, extending as close as practicable to the conductor ends.

The subject of protecting against primary-wire breakage arose from interpretations, in some regions, of IEC documents. We view this subject as a basic safety matter.

Pete Perkińs Product Safety Engineering Manager 58-262; Ext. 7374

Eddie Richmond Product Safety Engineer 58-262; Ext. 7374

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| For article ideas on subjects which affect either purchased or Tek-made components, feel free to call on us on ext. 6867. | For additions or changes to the mailing list, call Gloria (ext. 6867). |

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